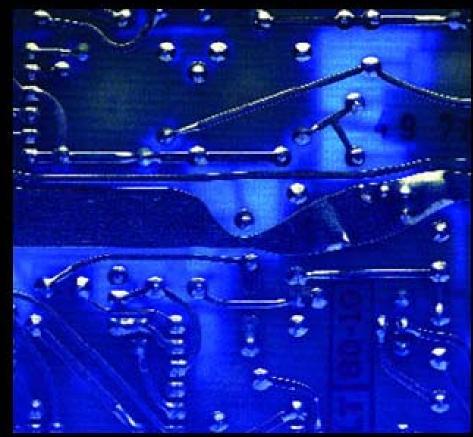
# **ELECTRONIC DEVICES AND CIRCUIT THEORY**

TENTH EDITION





**Chapter 6: Field-Effect Transistors** 

BOYLESTAD

# FETs vs. BJTs

### Similarities:

- Amplifiers
- Switching devices
- Impedance matching circuits

### **Differences:**

- FETs are voltage controlled devices. BJTs are current controlled devices.
- FETs have a higher input impedance. BJTs have higher gains.
- FETs are less sensitive to temperature variations and are more easily integrated on ICs.
- FETs are generally more static sensitive than BJTs.





•JFET: Junction FET

•MOSFET: Metal–Oxide–Semiconductor FET

**D-MOSFET:** Depletion MOSFET**E-MOSFET:** Enhancement MOSFET

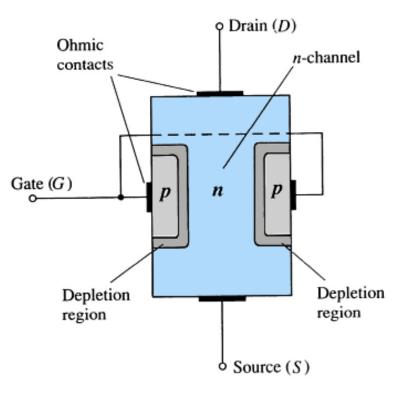


# **JFET Construction**

#### There are two types of JFETs

•*n*-channel •*p*-channel

The n-channel is more widely used.



There are three terminals:

•Drain (D) and Source (S) are connected to the *n*-channel •Gate (G) is connected to the *p*-type material



# **JFET Operation:** The Basic Idea

JFET operation can be compared to a water spigot.

**The source** of water pressure is the accumulation of electrons at the negative pole of the drain-source voltage.

The drain of water is the electron deficiency (or holes) at the positive pole of the applied voltage.

**The control** of flow of water is the gate voltage that controls the width of the n-channel and, therefore, the flow of charges from source to drain.





# **JFET Operating Characteristics**

There are three basic operating conditions for a JFET:

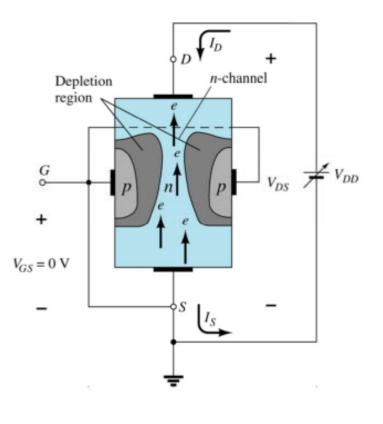
- $V_{GS} = 0$ ,  $V_{DS}$  increasing to some positive value
- $V_{GS} < 0$ ,  $V_{DS}$  at some positive value
- Voltage-controlled resistor



# JFET Operating Characteristics: V<sub>GS</sub> = 0 V

Three things happen when  $V_{GS}$  = 0 and  $V_{DS}$  is increased from 0 to a more positive voltage

- The depletion region between p-gate and n-channel increases as electrons from n-channel combine with holes from p-gate.
- Increasing the depletion region, decreases the size of the n-channel which increases the resistance of the n-channel.
- Even though the n-channel resistance is increasing, the current  $(I_D)$  from source to drain through the nchannel is increasing. This is because  $V_{DS}$  is increasing.

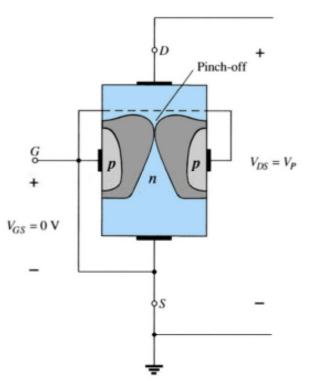




### **JFET Operating Characteristics:** Pinch Off

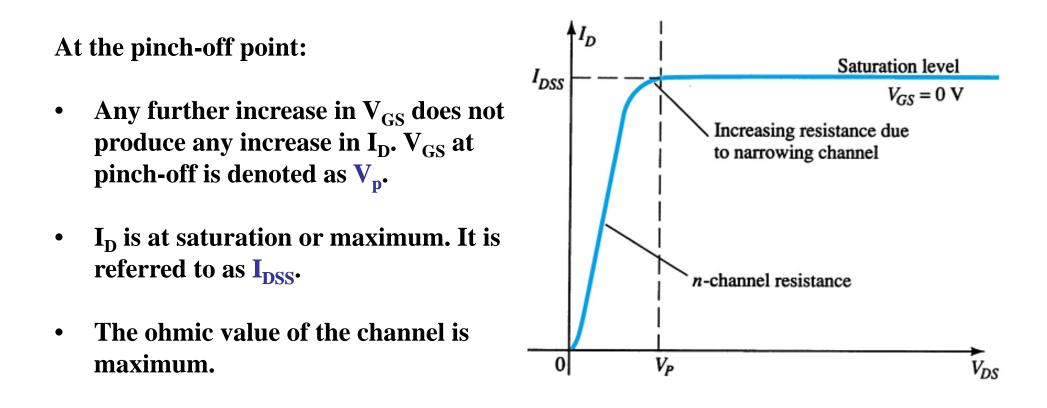
If  $V_{GS} = 0$  and  $V_{DS}$  is further increased to a more positive voltage, then the depletion zone gets so large that it **pinches off** the n-channel.

This suggests that the current in the nchannel ( $I_D$ ) would drop to 0A, but it does just the opposite-as  $V_{DS}$  increases, so does  $I_D$ .





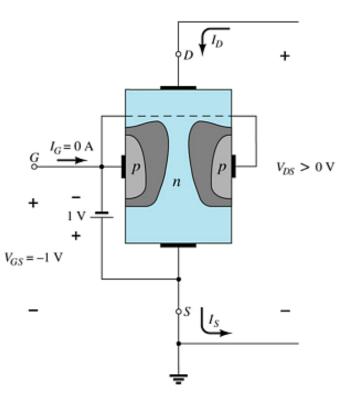
## **JFET Operating Characteristics:** Saturation





# **JFET Operating Characteristics**

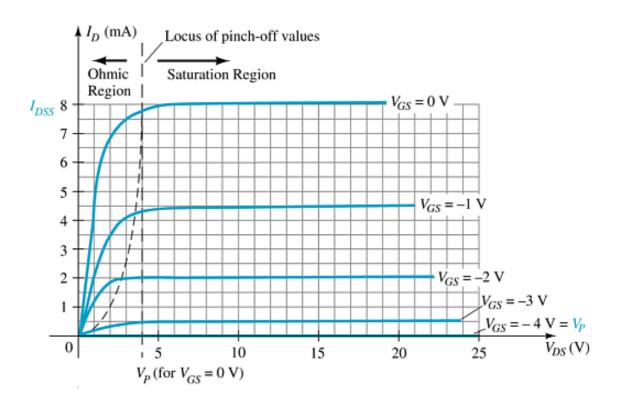
As  $V_{GS}$  becomes more negative, the depletion region increases.



# **JFET Operating Characteristics**

As V<sub>GS</sub> becomes more negative:

- The JFET experiences pinch-off at a lower voltage (V<sub>P</sub>).
- I<sub>D</sub> decreases (I<sub>D</sub> < I<sub>DSS</sub>) even though V<sub>DS</sub> is increased.
- Eventually  $I_D$  reaches 0 A.  $V_{GS}$  at this point is called  $V_p$  or  $V_{GS(off)}$ ..



Also note that at high levels of  $V_{DS}$  the JFET reaches a breakdown situation.  $I_D$  increases uncontrollably if  $V_{DS}$  >  $V_{DSmax}$ .

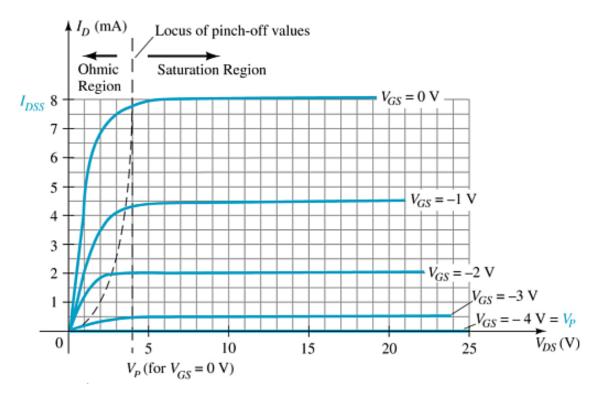


### JFET Operating Characteristics: Voltage-Controlled Resistor

The region to the left of the pinch-off point is called the ohmic region.

The JFET can be used as a variable resistor, where  $V_{GS}$  controls the drain-source resistance  $(r_d)$ . As  $V_{GS}$  becomes more negative, the resistance  $(r_d)$  increases.

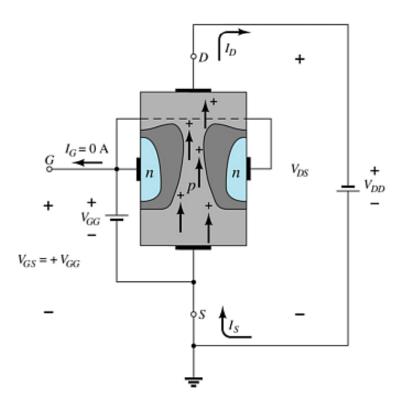
$$\mathbf{r_d} = \frac{\mathbf{r_0}}{\left(1 - \frac{\mathbf{V_{GS}}}{\mathbf{V_P}}\right)^2}$$





# **p-Channel JFETS**

The *p*-channel JFET behaves the same as the *n*-channel JFET, except the voltage polarities and current directions are reversed.

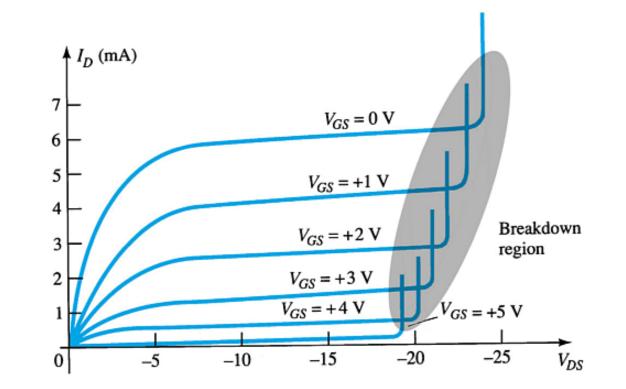




# **p-Channel JFET Characteristics**

As V<sub>GS</sub> increases more positively

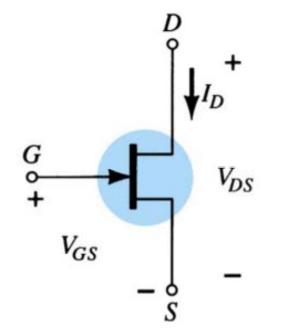
- The depletion zone increases
- $I_D$  decreases  $(I_D < I_{DSS})$
- Eventually  $I_D = 0 A$



Also note that at high levels of  $V_{DS}$  the JFET reaches a breakdown situation:  $I_D$  increases uncontrollably if  $V_{DS} > V_{DSmax}$ .



# **N-Channel JFET Symbol**





Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky

# **JFET** Transfer Characteristics

The transfer characteristic of input-to-output is not as straightforward in a JFET as it is in a BJT.

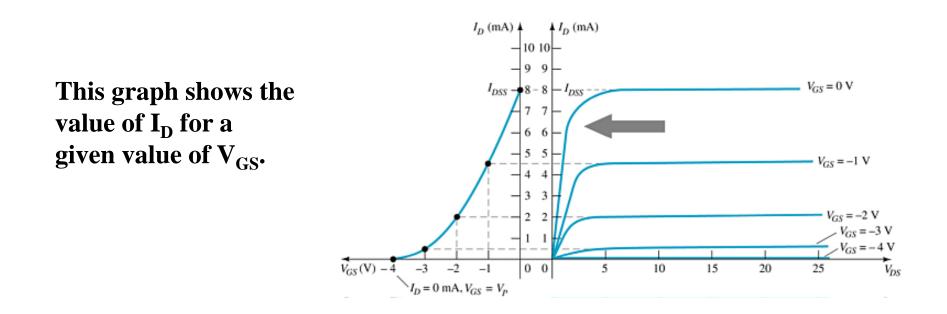
In a BJT,  $\beta$  indicates the relationship between  $I_B$  (input) and  $I_C$  (output).

In a JFET, the relationship of  $V_{GS}$  (input) and  $I_D$  (output) is a little more complicated:

$$\mathbf{I}_{\mathbf{D}} = \mathbf{I}_{\mathbf{DSS}} \left( 1 - \frac{\mathbf{V}_{\mathbf{GS}}}{\mathbf{V}_{\mathbf{P}}} \right)^2$$



### **JFET Transfer Curve**





# **Plotting the JFET Transfer Curve**

Using  $I_{DSS}$  and Vp ( $V_{GS(off)}$ ) values found in a specification sheet, the transfer curve can be plotted according to these three steps:

Step I  

$$I_D = I_{DSS} \left( 1 - \frac{V_{GS}}{V_P} \right)^2$$
  
Solving for  $V_{GS} = 0V$   $I_D = I_{DSS}$ 

Stop 1

Step 2  

$$I_D = I_{DSS} \left( 1 - \frac{V_{GS}}{V_P} \right)^2$$
  
Solving for  $V_{GS} = V_p \left( V_{GS(off)} \right) \ I_D = 0A$ 

#### Step 3

Solving for 
$$V_{GS} = 0V$$
 to  $V_p$   $I_D = I_{DSS} \left(1 - \frac{V_{GS}}{V_P}\right)^2$ 



# **JFET Specifications Sheet**

### **Electrical Characteristics**

ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise note	(b:				
Characteristic	Symbol	Min	Тур	Max	Unit

#### OFF CHARACTERISTICS

Gate-Source Breakdown Voltage (I <sub>G</sub> = -10 µAdc, V <sub>DS</sub> = 0)	V <sub>(BR)GSS</sub>	-25	-	-	Vdc
Gate Reverse Current $(V_{GS} = -15 \text{ Vdc}, V_{DS} = 0)$ $(V_{GS} = -15 \text{ Vdc}, V_{DS} = 0, T_A = 100^{\circ}\text{C})$	1 <sub>GSS</sub>	-	-	-1.0 -200	nAdc
Gate Source Cutoff Voltage (V <sub>DS</sub> = 15 Vdc, I <sub>D</sub> = 10 nAdc) 2N54	IS7 V <sub>GS(off)</sub>	-0.5	-	-6.0	Vdc
Gate Source Voltage $(V_{DS} = 15 \text{ Vdc}, I_D = 100 \ \mu \text{Adc})$ 2N54	157 V <sub>GS</sub>	-	-2.5	-	Vdc

#### ON CHARACTERISTICS

Zero-Gate-Voltage Drain Current* (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0) 2N5457	IDSS	1.0	3.0	5.0	mAde
--	------	-----	-----	-----	------

#### SMALL-SIGNAL CHARACTERISTICS

Forward Transfer Admittance Common Source* (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0, f = 1.0 kHz) 2N5457	lYed	1000	-	5000	µmhos
Output Admittance Common Source* (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0, f = 1.0 kHz)	lYod	-	10	50	µmhos
Input Capacitance (V <sub>DS</sub> = 15 Vdc, V <sub>GS</sub> = 0, f = 1.0 MHz)	Ciss	-	4.5	7.0	pF
Reverse Transfer Capacitance (V <sub>DS</sub> = 15 Vdc, V <sub>OS</sub> = 0, f = 1.0 MHz)	Crss	-	1.5	3.0	pF

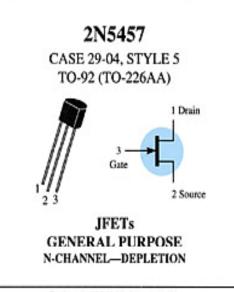
\*Pulse Test: Pulse Width \$ 630 ms; Duty Cycle \$10%



# **JFET Specifications Sheet**

### **Maximum Ratings**

Rating	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DS</sub>	25	Vdc
Drain-Gate Voltage	V <sub>DG</sub>	25	Vdc
Reverse Gate-Source Voltage	VGSR	-25	Vdc
Gate Current	IG	10	mAdc
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	PD	310 2.82	mW mW/°C
Junction Temperature Range	Tj	125	.с
Storage Channel Temperature Range	Tstg	-65 to +150	.C



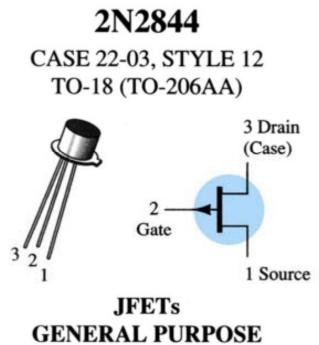
Refer to 2N4220 for graphs.

#### more...



Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky

# **Case and Terminal Identification**



P-CHANNEL



# **Testing JFETs**

• Curve Tracer

A curve tracer displays the  $I_D$  versus  $V_{DS}$  graph for various levels of  $V_{GS}.$ 

• Specialized FET Testers

These testers show  $I_{DSS}$  for the JFET under test.



### **MOSFETs**

**MOSFETs have characteristics similar to JFETs and additional characteristics that make then very useful.** 

There are two types of MOSFETs:

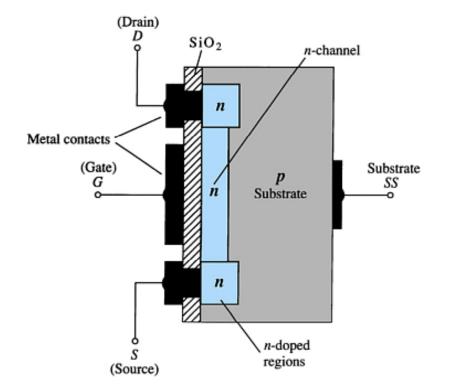
- Depletion-Type
- Enhancement-Type



# **Depletion-Type MOSFET Construction**

The Drain (D) and Source (S) connect to the to *n*-doped regions. These *n*doped regions are connected via an *n*channel. This *n*-channel is connected to the Gate (G) via a thin insulating layer of SiO<sub>2</sub>.

The *n*-doped material lies on a *p*-doped substrate that may have an additional terminal connection called Substrate (SS).

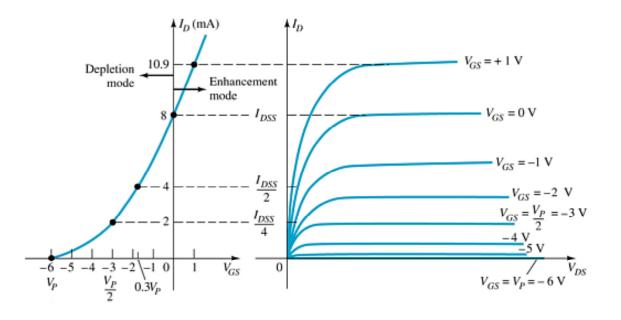




# **Basic MOSFET Operation**

A depletion-type MOSFET can operate in two modes:

- Depletion mode
- Enhancement mode

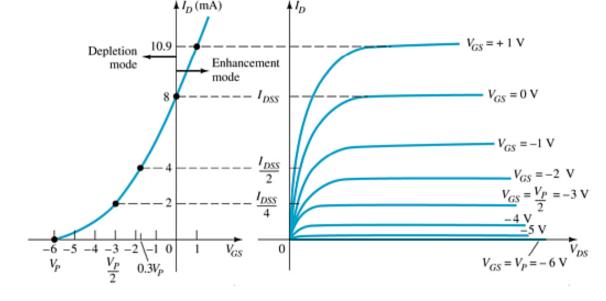




# **D-Type MOSFET in Depletion Mode**

**Depletion Mode** 

The characteristics are similar to a JFET.



- When  $V_{GS} = 0$  V,  $I_D = I_{DSS}$
- When  $V_{GS} < 0$  V,  $I_D < I_{DSS}$
- The formula used to plot the transfer curve still applies:

$$\mathbf{I}_{\mathbf{D}} = \mathbf{I}_{\mathbf{DSS}} \left( 1 - \frac{\mathbf{V}_{\mathbf{GS}}}{\mathbf{V}_{\mathbf{P}}} \right)^2$$



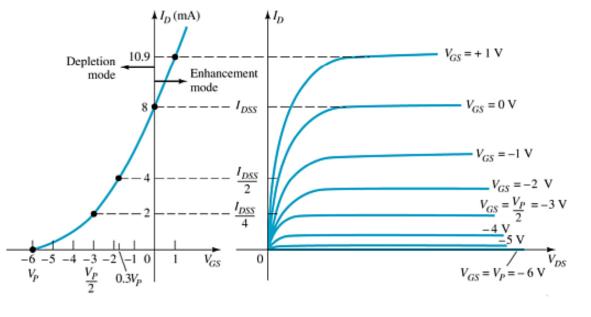
# **D-Type MOSFET in Enhancement Mode**

### **Enhancement Mode**

- $V_{GS} > 0 V$
- I<sub>D</sub> increases above I<sub>DSS</sub>
- The formula used to plot the transfer curve still applies:

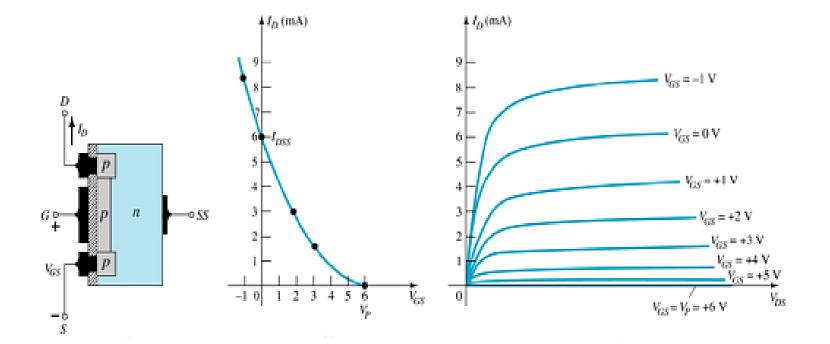
$$I_{D} = I_{DSS} \left( 1 - \frac{V_{GS}}{V_{P}} \right)^{2}$$

Note that V<sub>GS</sub> is now a positive polarity





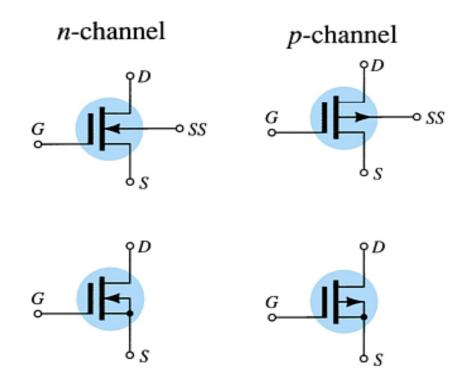
# p-Channel D-Type MOSFET





Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky

# **D-Type MOSFET Symbols**





Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky

# **Specification Sheet**

#### **Maximum Ratings**

				2N3797
				CASE 22-03, STYLE 2 TO-18 (TO-206AA)
MAXIMUM RATINGS Rating	Symbol	Value	Unit	Gase F
Drain-Source Voltage 2N3797	V <sub>DS</sub>	20	Vdc	3
Gate-Source Voltage	VGS	±10	Vdc	2 - 1 1 Sou
Drain Current	ID	20	mAdc	MOSFETs
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	PD	200 1.14	mW mW/°C	LOW POWER AUDIO
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C Junction Temperature Range	P <sub>D</sub> T <sub>J</sub>			

#### more...



1 Source

## **Specification Sheet**

### **Electrical Characteristics**

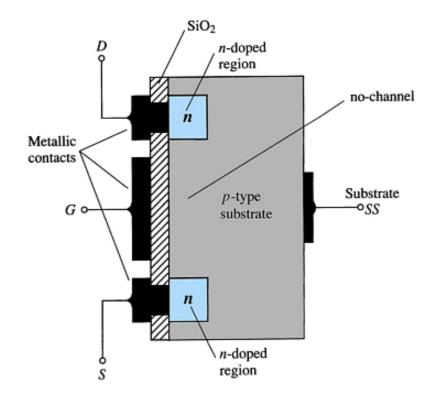
Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain Source Breakdown Voltage (V <sub>OS</sub> = -7.0 V, I <sub>D</sub> = 5.0 µA)	2N3797	V <sub>(BR)DSX</sub>	20	25	-	Vdc
Gate Reverse Current (1) $(V_{CS} = -10 \text{ V}, V_{DS} = 0)$ $(V_{CS} = -10 \text{ V}, V_{DS} = 0, T_A = 150^{\circ}\text{C})$		Lass		-	1.0 200	pAdc
Gate Source Cutoff Voltage (I <sub>D</sub> = 2.0 µA, V <sub>DS</sub> = 10 V)	2N3797	V <sub>GS(off)</sub>	-	-5.0	-7.0	Vdc
Drain-Gate Reverse Current (1) (V <sub>DG</sub> = 10 V, I <sub>S</sub> = 0)		IDCO		1.0	1.0	pAdc
ON CHARACTERISTICS						
Zero-Gate-Voltage Drain Current $(V_{DS} = 10 \text{ V}, V_{GS} = 0)$	2N3797	I <sub>DSS</sub>	2.0	2.9	6.0	mAde
On-State Drain Current ( $V_{DS} = 10$ V, $V_{CS} = +3.5$ V)	2N3797	I <sub>D(mt)</sub>	9.0	14	18	mAdc
SMALL-SIGNAL CHARACTERISTICS						
Forward Transfer Admittance (V <sub>DS</sub> = 10 V, V <sub>CS</sub> = 0, f = 1.0 kHz)	2N3797	Y <sub>fs</sub>	1500	2300	3000	µmho
$(V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz})$	2N3797		1500	122	-	
Output Admittance $(I_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0, \text{ f} = 1.0 \text{ kHz})$	2N3797	l Yosl	-	27	60	µmho
Input Capacitance $(V_{DS}=10~V,~V_{GS}=0,~f=1.0~MHz)$	2N3797	Cisa	-	6.0	8.0	pF
Reverse Transfer Capacitance (V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0, f = 1.0 MHz)		Cna	-	0.5	0.8	bk
FUNCTIONAL CHARACTERISTICS						
Noise Figure (V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0, f = 1.0 kHz, R <sub>S</sub> = 3 mepohms)		NF	-	3.8	100	dB

 This value of current includes both the FET leakage current as well as the leakage current associated with the test socket and fixture when measured under best attainable conditions.



# **E-Type MOSFET Construction**

- The Drain (D) and Source (S) connect to the to *n*-doped regions. These *n*doped regions are connected via an *n*channel
- The Gate (G) connects to the *p*-doped substrate via a thin insulating layer of SiO<sub>2</sub>
- There is no channel
- The *n*-doped material lies on a *p*-doped substrate that may have an additional terminal connection called the Substrate (SS)

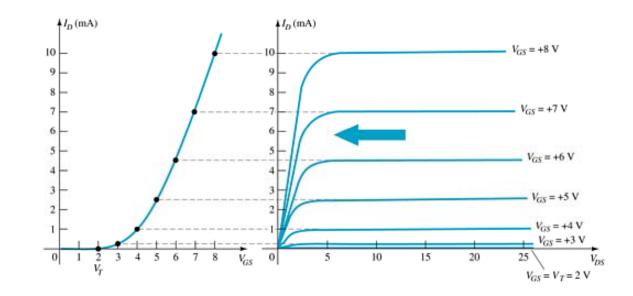




# **Basic Operation of the E-Type MOSFET**

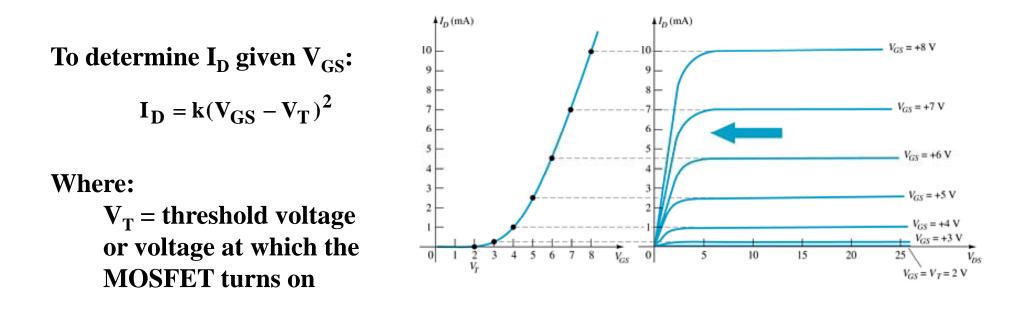
### The enhancement-type MOSFET operates only in the enhancement mode.

- V<sub>GS</sub> is always positive
- As V<sub>GS</sub> increases, I<sub>D</sub> increases
- As  $V_{GS}$  is kept constant and  $V_{DS}$  is increased, then  $I_D$  saturates  $(I_{DSS})$ and the saturation level,  $V_{DSsat}$  is reached





# **E-Type MOSFET Transfer Curve**



k, a constant, can be determined by using values at a specific point and the formula:

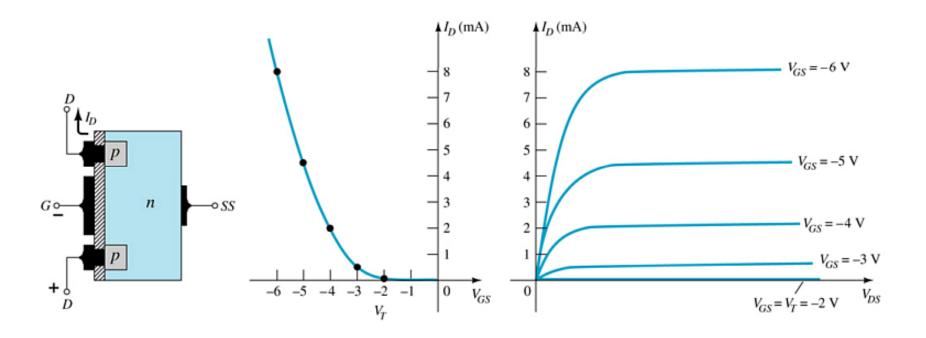
$$k = \frac{I_{D(ON)}}{\left(V_{GS(ON)} - VT\right)^2}$$

**V**<sub>DSsat</sub> can be calculated by:

$$V_{Dsat} = V_{GS} - V_T$$



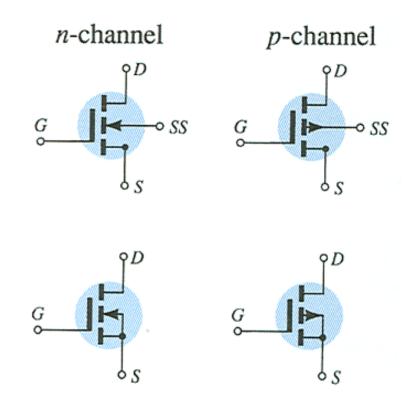
# *p*-Channel E-Type MOSFETs



The *p*-channel enhancement-type MOSFET is similar to the *n*channel, except that the voltage polarities and current directions are reversed.



# **MOSFET Symbols**





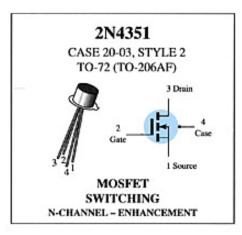
Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky

# **Specification Sheet**

#### **Maximum Ratings**

Rating	Symbol	Value	Unit
Drain-Source Voltage	VDS	25	Vdc
Drain-Gate Voltage	V <sub>DG</sub>	30	Vdc
Gate-Source Voltage*	V <sub>GS</sub>	30	Vdc
Drain Current	ID	30	mAdc
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	PD	300 1.7	mW mW/°C
Junction Temperature Range	Tj	175	°C
Storage Temperature Range	Tatg	-65 to +175	°C





#### more...



### **Specification Sheet**

#### **Electrical Characteristics**

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Drain-Source Breakdown Voltage $(I_D = 10 \ \mu A, V_{GS} = 0)$	V <sub>(BR)DSX</sub>	25	-	Vdc
Zero-Gate-Voltage Drain Current $(V_{DS} = 10 \text{ V}, V_{GS} = 0) \text{ T}_A = 25^{\circ}\text{C}$ $\text{T}_A = 150^{\circ}\text{C}$	L <sub>DSS</sub>		10 10	nAdc µAdc
Gate Reverse Current ( $V_{GS} = \pm 15 \text{ Vdc}, V_{DS} = 0$ )	I <sub>GSS</sub>	-	± 10	pAdc
ON CHARACTERISTICS				
Gate Threshold Voltage $(V_{DS} = 10 V, I_D = 10 \mu A)$	V <sub>GS(Th)</sub>	1.0	5	Vdc
Drain-Source On-Voltage (1 <sub>D</sub> = 2.0 mA, V <sub>GS</sub> = 10V)	V <sub>DS(on)</sub>	-	1.0	v
On-State Drain Current (V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 10 V)	I <sub>D(on)</sub>	3.0	-	mAde
SMALL-SIGNAL CHARACTERISTICS				
Forward Transfer Admittance $(V_{DS} = 10 \text{ V}, I_D = 2.0 \text{ mA}, f = 1.0 \text{ kHz})$	y <sub>fs</sub>	1000	-	µmho
Input Capacitance (V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0, f = 140 kHz)	C <sub>iss</sub>	( <del>-</del> )	5.0	pF
Reverse Transfer Capacitance $(V_{DS} = 0, V_{GS} = 0, f = 140 \text{ kHz})$	C <sub>ns</sub>	1	1.3	pF
Drain-Substrate Capacitance (V <sub>D(SUB)</sub> = 10 V, f = 140 kHz)	C <sub>d(sub)</sub>	-	5.0	pF
Drain-Source Resistance ( $V_{GS} = 10 \text{ V}, I_D = 0, f = 1.0 \text{ kHz}$ )	fds(on)	-	300	ohms
SWITCHING CHARACTERISTICS			2.000	
Turn-On Delay (Fig. 5)	t <sub>d1</sub>	-	45	ns
Rise Time (Fig. 6) $I_D = 2.0 \text{ mAde}, V_{DS} = 10 \text{ Vde},$ (V <sub>GS</sub> = 10 Vde)	t <sub>r</sub>	1	65	ns
Turn-Off Delay (Fig. 7) (VGS = 10 Vdc) (See Figure 9; Times Circuit Determined)	1 <sub>d2</sub>	-	60	ns
Fall Time (Fig. 8)	tr	-	100	ns

PEARSON

# Handling MOSFETs

MOSFETs are very sensitive to static electricity. Because of the very thin SiO<sub>2</sub> layer between the external terminals and the layers of the device, any small electrical discharge can create an unwanted conduction.

### Protection

- Always transport in a static sensitive bag
- Always wear a static strap when handling MOSFETS
- •
- Apply voltage limiting devices between the gate and source, such as back-to-back Zeners to limit any transient voltage.

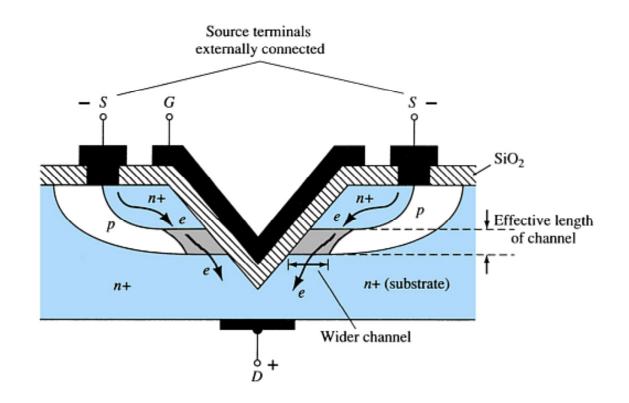


# **VMOS Devices**

VMOS (vertical MOSFET) increases the surface area of the device.

### Advantages

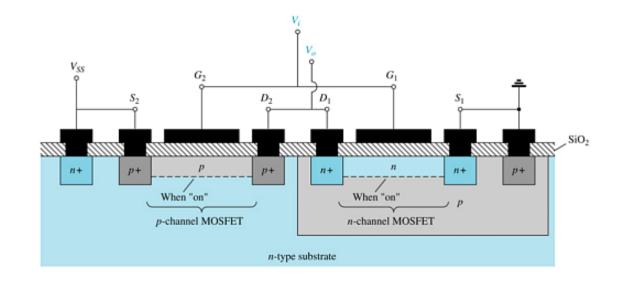
- VMOS devices handle higher currents by providing more surface area to dissipate the heat.
- VMOS devices also have faster switching times.





# **CMOS Devices**

CMOS (complementary MOSFET) uses a *p*-channel and *n*-channel MOSFET; often on the same substrate as shown here.

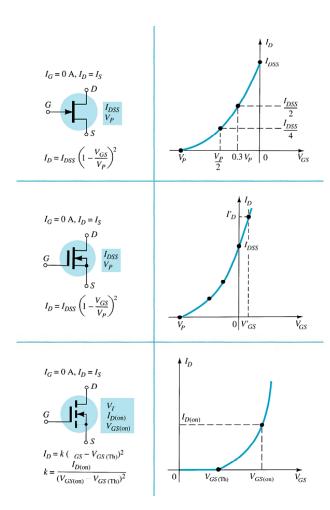


### Advantages

- Useful in logic circuit designs
- Higher input impedance
- Faster switching speeds
- Lower operating power levels



# **Summary Table**





Electronic Devices and Circuit Theory, 10/e Robert L. Boylestad and Louis Nashelsky